

Notice of References Cited	Application/Control No. 10/764,241	Applicant(s)/Patent Under Reexamination CHANG, CHIEN-JEN	
	Examiner Sarvesh J. Nadkarni	Art Unit 2629	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0025718	02-2003	Mori, Makiko	345/690
*	B	US-2003/0006952	01-2003	Hong, Hyung Ki	345/89
*	C	US-2002/0180680	12-2002	Moon, Seung-Hwan	345/89
*	D	US-2003/0058211	03-2003	Kim et al.	345/89
*	E	US-2001/0033260	10-2001	Nishitani et al.	345/87
*	F	US-2002/0063670	05-2002	Yoshinaga et al.	345/87
*	G	US-2003/0151565	08-2003	Kim et al.	345/60
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.